

## PowerMOS transistor

BUK455-600B

## GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic envelope.  
The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

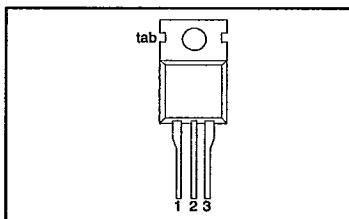
## QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
$V_{DS}$	Drain-source voltage	600	V
$I_D$	Drain current (DC)	4.0	A
$P_{tot}$	Total power dissipation	100	W
$R_{DS(on)}$	Drain-source on-state resistance	2.5	$\Omega$

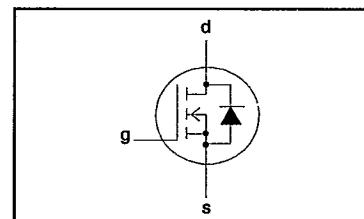
## PINNING - TO220AB

PIN	DESCRIPTION
1	gate
2	drain
3	source
tab	drain

## PIN CONFIGURATION



## SYMBOL



## LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DS}$	Drain-source voltage	-	-	600	V
$V_{DGR}$	Drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	600	V
$\pm V_{GS}$	Gate-source voltage	-	-	30	V
$I_D$	Drain current (DC)	$T_{mb} = 25^\circ\text{C}$	-	4.0	A
$I_D$	Drain current (DC)	$T_{mb} = 100^\circ\text{C}$	-	2.5	A
$I_{DM}$	Drain current (pulse peak value)	$T_{mb} = 25^\circ\text{C}$	-	16	A
$P_{tot}$	Total power dissipation	$T_{mb} = 25^\circ\text{C}$	-	100	W
$T_{sg}$	Storage temperature	$T_{mb} = 25^\circ\text{C}$	-55	150	$^\circ\text{C}$
$T_j$	Junction Temperature	-	-	150	$^\circ\text{C}$

## THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{lh,j(mb)}$	Thermal resistance junction to mounting base	-	-	-	1.25	K/W
$R_{lh,j(a)}$	Thermal resistance junction to ambient	-	-	60	-	K/W

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## STATIC CHARACTERISTICS

 $T_{mb} = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	600	-	-	V
$V_{GS(0)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 600 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$	-	2	20	$\mu\text{A}$
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 600 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125^\circ\text{C}$	-	0.1	1.0	mA
$I_{GSS}$	Gate source leakage current	$V_{DS} = \pm 30 \text{ V}; V_{GS} = 0 \text{ V}$	-	10	100	nA
$R_{DS(on)}$	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 2.5 \text{ A}$	-	2.1	2.5	$\Omega$

## DYNAMIC CHARACTERISTICS

 $T_{mb} = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$g_{fs}$	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 2.5 \text{ A}$	2.5	4.5	-	S
$C_{iss}$	Input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	750	1000	pF
$C_{oss}$	Output capacitance		-	90	140	pF
$C_{rss}$	Feedback capacitance		-	40	70	pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30 \text{ V}; I_D = 2.6 \text{ A};$	-	10	45	ns
$t_r$	Turn-on rise time	$V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega;$	-	45	60	ns
$t_{d(off)}$	Turn-off delay time	$R_{gen} = 50 \Omega$	-	100	140	ns
$t_f$	Turn-off fall time		-	40	65	ns
$L_d$	Internal drain inductance	Measured from contact screw on tab to centre of die	-	3.5	-	nH
$L_d$	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	4.5	-	nH
$L_s$	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	7.5	-	nH

## REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS

 $T_{mb} = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_{DR}$	Continuous reverse drain current	-	-	-	4.5	A
$I_{DRM}$	Pulsed reverse drain current	-	-	-	18	A
$V_{SD}$	Diode forward voltage	$I_F = 4.5 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.1	1.5	V
$t_r$	Reverse recovery time	$I_F = 4.5 \text{ A}; -di_F/dt = 100 \text{ A}/\mu\text{s};$	-	1200	-	ns
$Q_r$	Reverse recovery charge	$V_{GS} = 0 \text{ V}; V_R = 100 \text{ V}$	-	6.0	-	$\mu\text{C}$

Philips Semiconductors

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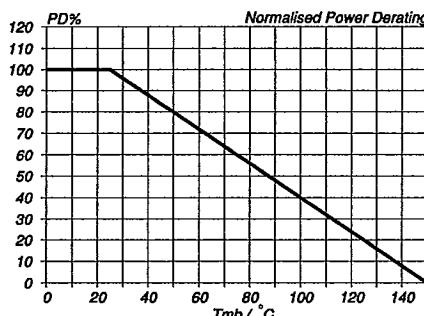


Fig. 1. Normalised power dissipation.  
 $PD\% = 100 \cdot P_D / P_{D\ 25^\circ C} = f(T_{mb})$

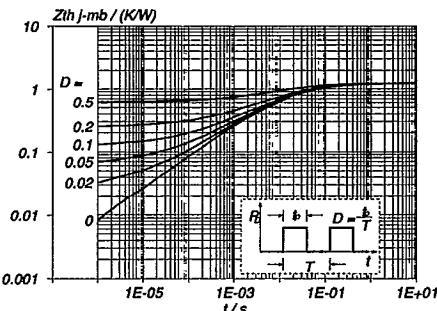


Fig. 4. Transient thermal impedance.  
 $Z_{thJ-mb} = f(t); \text{parameter } D = t/T$

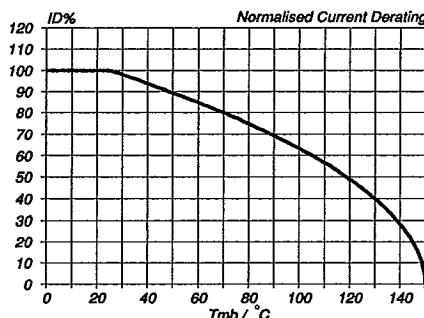


Fig. 2. Normalised continuous drain current.  
 $ID\% = 100 \cdot I_D / I_{D\ 25^\circ C} = f(T_{mb}); \text{conditions: } V_{GS} \geq 10 \text{ V}$

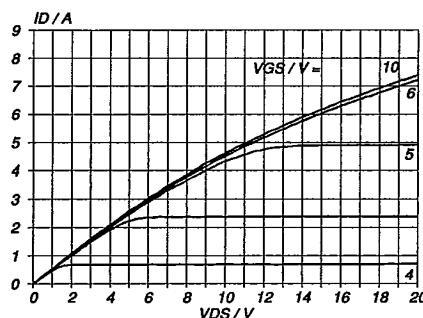


Fig. 5. Typical output characteristics,  $T_J = 25^\circ C$ .  
 $I_D = f(V_{DS}); \text{parameter } V_{GS}$

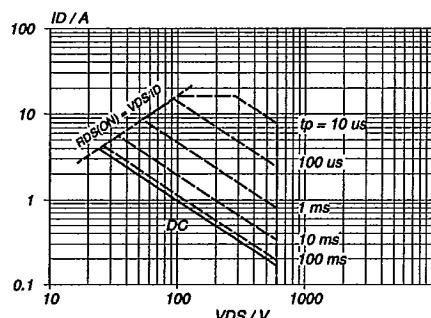


Fig. 3. Safe operating area.  $T_{mb} = 25^\circ C$   
 $I_D \& I_{DM} = f(V_{DS}); I_{DM} \text{ single pulse}; \text{parameter } t_p$

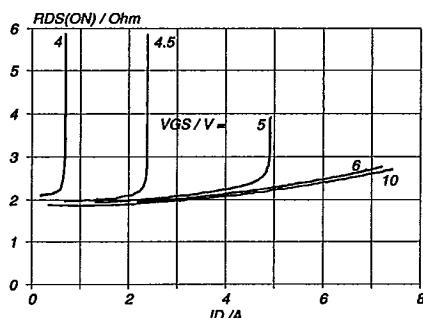


Fig. 6. Typical on-state resistance,  $T_J = 25^\circ C$ .  
 $R_{DS(ON)} = f(I_D), \text{parameter } V_{GS}$

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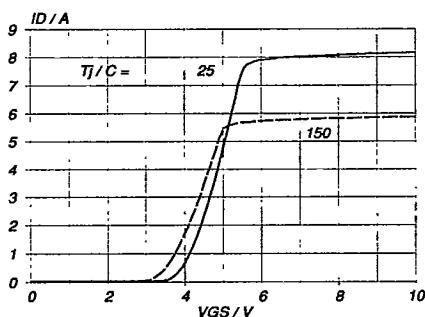


Fig.7. Typical transfer characteristics.  
 $I_D = f(V_{GS})$ ; conditions:  $V_{DS} = 25\text{ V}$ ; parameter  $T_J$

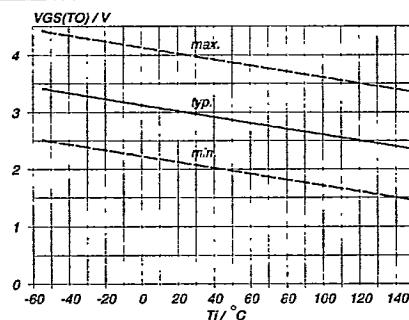


Fig.10. Gate threshold voltage.  
 $V_{GS(TO)} = f(T_J)$ ; conditions:  $I_D = 1\text{ mA}$ ;  $V_{DS} = V_{GS}$

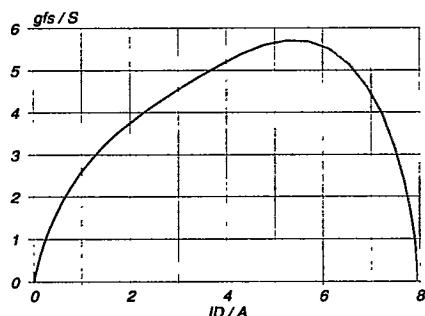


Fig.8. Typical transconductance,  $T_J = 25^\circ\text{C}$ .  
 $g_{fs} = f(I_D)$ ; conditions:  $V_{DS} = 25\text{ V}$

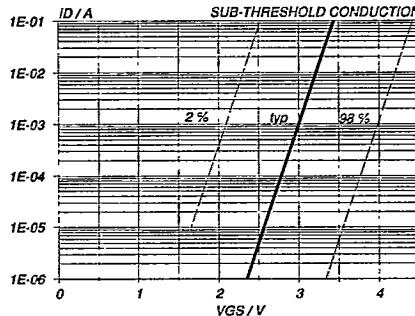


Fig.11. Sub-threshold drain current.  
 $I_D = f(V_{GS})$ ; conditions:  $T_J = 25^\circ\text{C}$ ;  $V_{DS} = V_{GS}$

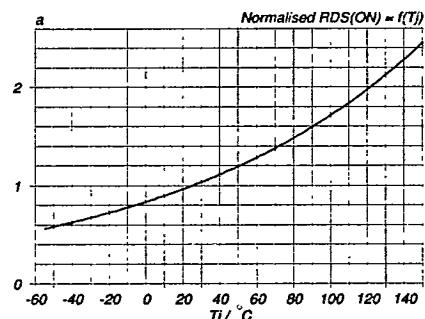


Fig.9. Normalised drain-source on-state resistance.  
 $a = R_{DS(ON)}/R_{DS(ON)/25^\circ\text{C}} = f(T_J)$ ;  $I_D = 2.5\text{ A}$ ;  $V_{GS} = 10\text{ V}$

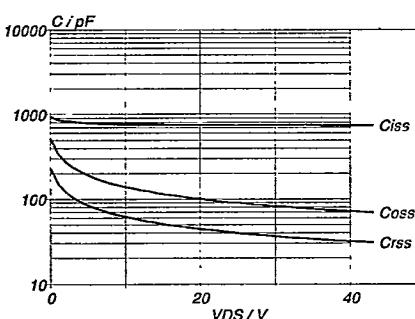


Fig.12. Typical capacitances,  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$ .  
 $C = f(V_{DS})$ ; conditions:  $V_{GS} = 0\text{ V}$ ;  $f = 1\text{ MHz}$

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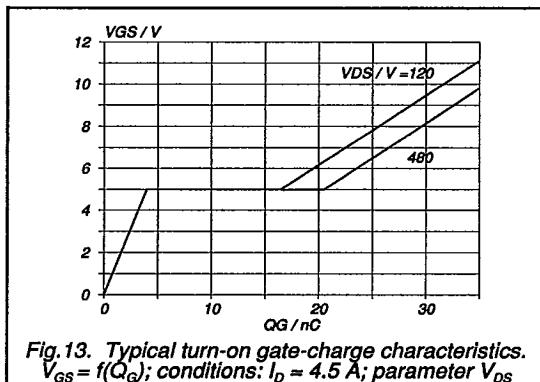


Fig.13. Typical turn-on gate-charge characteristics.  
 $V_{GS} = f(Q_G)$ ; conditions:  $I_D = 4.5 \text{ A}$ ; parameter  $V_{DS}$

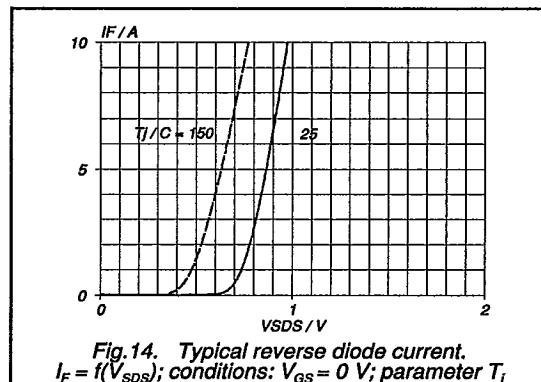


Fig.14. Typical reverse diode current.  
 $I_F = f(V_{DS})$ ; conditions:  $V_{GS} = 0 \text{ V}$ ; parameter  $T_j$